

Industrial Color Linear Camera

- ★ True color
- ★ High resolution
- ★ Wider view angle
- ★ Good value



JJ-C5615-6K



JJ-C5615-12K

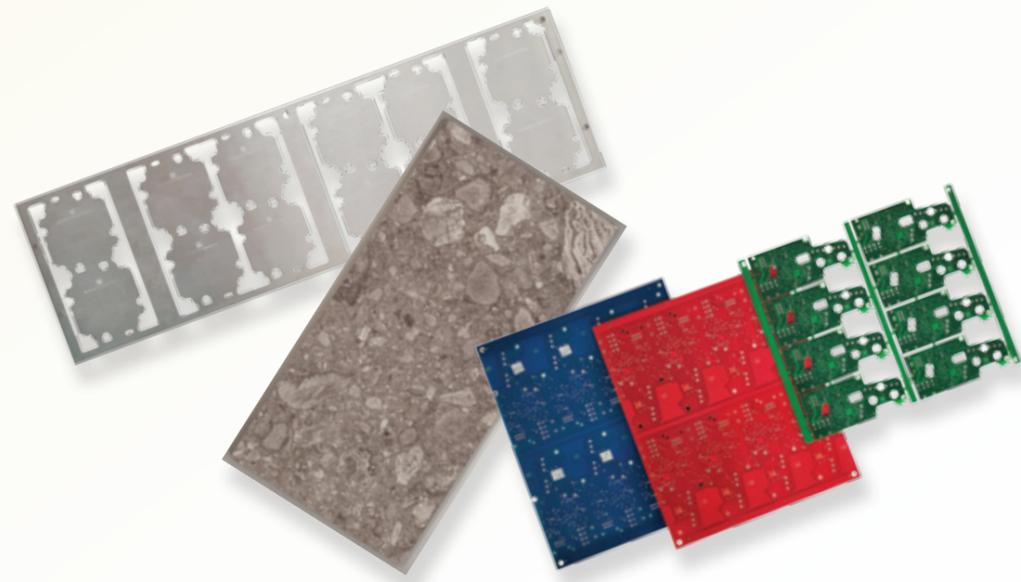


MLCA75-12K



MLCA73-18K

Image Sensor	Color Linear CCD	Color Linear CCD	Color Linear CCD	Color Linear CCD
Effective Pixels	5500 pixels x 3 lines	5500 pixels x 3 lines	7500 pixels x 3 lines	7300 pixels x 3 lines
Interface	CameraLink® Base	CameraLink® Medium	Camera Link® Medium	Camera Link® Medium
Line Frequency	6.25k line / sec.	12.5k line /sec.	12.5k line / sec.	17.5k line / sec.
Lens Mount	Built-in Lens	Built-in Lens	M72 x 0.75	M72 x 0.75
Scanning Width	11" (279.4 mm)	11" (279.4 mm)		
Working Distance	90 mm	90 mm		



Industrial Inspection System Imaging Solution

Accurate
Customization

Speed
www.microtek.com



Industrial Inspections and Applications Image Capturing System in High-Speed

Image Capturing System in High-Speed, introduced by Microtek, adopts a high-speed and high-resolution color linear camera exclusively used in industrial inspections. With customized and professional image capturing technology, it can catch details of the target moving in fast motion and then load these saved images into the software. Then, users are able to find out and mark up where defects are based on the predefined parameter settings. Thus, the system can enhance the quality control efficiently.

Features

- Customized designs guarantee the best outputs
- Suitable for using in various defect inspections, such as PCB, proofing, texture surfaces, holes on copper foils, latitudes and longitudes of glass fabrics and flat displays

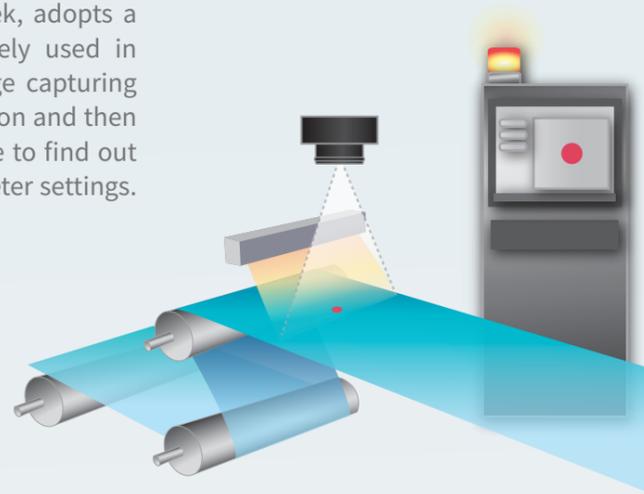


Image Inspection

Industrial Color Linear Camera

Inspecting System

Scanning and Inspecting Module FAI-630

FAI-630 is a non-contact color linear image capturing module, which is suitable for using together with various conveyors in order to capture large-scale images precisely. With the resolution is up to 20μm, the scanning area is up to 12 x 24 inches and the working distance is up to 2.5 cm, FAI-630 works best for FAI or identifying, comparing and inspecting images of PWBA before pasting solder. The working distance of the FAI-630 can be customized according to customers' demands.

Features

- Non-contact image capturing technology ensures the completeness of scanned targets
- Using together with different angles of lights to capture images of scanned targets and presents characteristics of different materials clearly
- Perfect for assembled on various transporting apparatus
- Images contains abundant information and suitable for adopted by AOI, for example, defect detections and image recognition

Specifications

- Sensor Type: Color CCD
- Resolution: 20μm
- Scanning Area: 12 x 24 inches
- Working Distance: 2.5 cm



Using for Traceability In-line Barcode Inspection System

Users can set up a barcode inspection station based on sizes of the existing production lines. Using the image scanning technology together with the analyzation technique, users are able to inspect availability of products fast and thus enhance the quality control.

Features

- Capable to inspect Data Matrix and QR codes
- Meets with the standard of SMEMA
- Exclusively-designed software enhances inspections effectively

Specifications

- Height (From the ground to the conveyor): 90-110 cm
- Width of the conveyor: 10-36 cm (Adjustable)

Inspections and Applications for The Semiconductor Industry Chain Defect Inspection Solution for IC Appearances

Because of some unique characteristics, such as small sizes, dedicated structures and large quantities, users will need a precise and effective tool to inspect IC chips. ObjectScan, a line of products come from Microtek, is a non-contact flat scanner. Equipped with the resolution up to 20μm, large-scale scanning area up to 52 x 38 cm and image readability of multiple IC chips at one time, ObjectScan allows users to find out chips with defects fast when using them together with a specially-designed software.



Features

- Supports image scanning of various IC surfaces
- Users can set up golden samples according to their needs; then, the system will automatically identify locations of all chips and perform defect inspections
- Users can process Smart Search by using odd numbers, inspecting items, or point reading
- Exclusively-designed software can be set up as PC-accessible or website-accessible

Specifications

- Scanning Area: 52 x 38 cm
- Working Distance: 7 cm
- Others: Allows users to set up defect categories according to their needs; allows users to perform a specific search by using defect items or uploading dates

